

<b>Notice of References Cited</b>	Application/Control No. 10/575,409		Applicant(s)/Patent Under Reexamination YU ET AL.	
	Examiner HEE-YONG KIM		Art Unit 2621	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0187634 A1	10-2003	Li, Jin	704/200.1
*	B	US-2005/0231396 A1	10-2005	Dunn, Chris	341/050
*	C	US-2005/0252361 A1	11-2005	Oshikiri, Masahiro	084/605
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

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	N					
	O					
	P					
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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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